



Schedule of Scope to Certificate of Approval Independent Testing Laboratory

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Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

Description test	Standard
High Temperature Operation test (HTOL)	JESD22-A108, AEC-Q100, AEC-Q200, MIL-STD-202
Low Temperature Operating Life (LTOL)	JESD22-A108
High Temperature Forward Bias (HTFB)	JESD22-A108
High Temperature Gate Bias (HTGB)	JESD22-A108, AEC-Q101
High Temperature Reverse Bias (HTRB)	JESD22-A108, AEC-Q101, MIL-STD-750, MIL-STD-883
Early Life Failure Rate (ELFR)	JESD22-A108, AEC-Q100
Highly Accelerated Stress Test (HAST)	JESD22-A110, AEC-Q100, AEC-Q101
Steady-Status Temperature and Humidity Bias Life Test (THB)	JESD22-A101, AEC-Q100, AEC-Q101, AEC-Q200, MIL-STD-202
Power and Temperature Cycling (PTC)	JESD22-A105, AEC-Q100, AEC-Q101
Electromigration (EM)	JEP001, JESD61, JESD87, AEC-Q100,
Stress Migration (SM)	JEP001, JEP139, JESD87, AEC-Q100,
Steady-Status operation life	MIL-STD-750, MIL-STD-883
Solderability test	J-STD-020, JESD22-B102

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